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SERIAL NUMBER 08/511,742	CLASS 43F	SUBCLASS 520	GROUP ART UNIT 0523
FILING DATE 03/08/97		EXAMINER K. N. N. N.	

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CONTINUING DATA *****
VERIFIED THIS APPLN IS A CON OF 08/462,742 06/05/95 5,604,360
WHICH IS A DIV OF 08/248,220 05/24/94 PAT

FOREIGN/ECT APPLICATIONS *****
VERIFIED JAPAN 5-147001 05/26/93

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Foreign priority claimed 35 USC 119 conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	AS FILED	STATE OR COUNTRY JPX	SHEETS DRWS. 7	TOTAL CLAIMS 25	INDEP. CLAIMS 9	FILING FEE RECEIVED \$1,360.00	ATTORNEY'S DOCKET NO. 0756-1641
Verified and Acknowledged Examiner's Initials SIXLEY, FRIEDMAN, LEEDOM & FERGUSON 2010 CORPORATE RIDGE SUITE 600 MCLEAN, VA 22102								
TITLE SEMICONDUCTOR DEVICE AND FABRICATION METHOD OF THE SAME								
U.S. DEPT. OF COMM./PAT. & TM - PTO-436L (Rev.12-84)								

Assistant Examiner	CLAIMS ALLOWED	
	Total Claims	Granted
	DRAWINGS	
	Sheets Drawn	
Primary Examiner	ISSUE BATCH NUMBER	
PREPARED FOR ISSUE		
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